# DENTONVACUUM



**Enabling Innovation** 

### INFINITY RM ION BEAM DEPOSITION AND ETCH SYSTEM

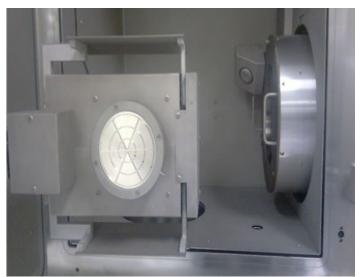
The Infinity RM Ion Beam Deposition and Etch System provides a versatile solution to perform deposition and etch within a single system for the most demanding and challenging applications.

#### **BENEFITS INCLUDE:**

- Independent control of ion energy and flux provides control of film microstructure, stoichiometry, and stress
- Stable deposition rates enable excellent control of film thickness and uniformity
- Second ion source for etch, ion-assisted deposition and pre-clean
- Easy-to-use software to provide a seamless and intuitive way to control the system



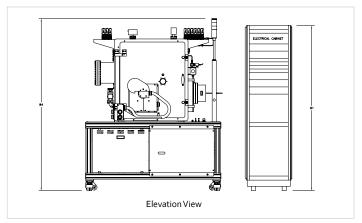


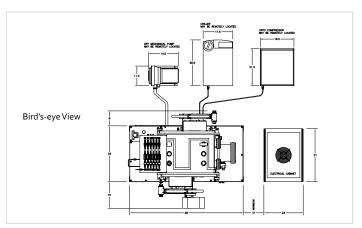


Infinity RM Chamber Internal View



## INFINITY RM ION BEAM DEPOSITION AND ETCH SYSTEM





Infinity RM Ion Beam Etch and Deposition System Schematic

#### INFINITY RM ION BEAM DEPOSITION AND ETCH SYSTEM SPECIFICATIONS

# Process System

- Inert or reactive gas in either source (RIBE)
- Wide variety of targets available including metals, dielectrics, ceramics, glasses, and refractory materials
- Reactive or non-reactive process (e.g. Si or SiO<sub>2</sub> or Si<sub>3</sub>N<sub>4</sub> can be deposited from a Si target)
- Pre-clean for excellent interface/adhesion
- Assist for control of film stress, density, stoichiometry by adding oxygen/nitrogen through the assist, and index
- Single wafer, up to 8-inch Ø
- Separate etch/assist/pre-clean and deposition sources
- Water cooled substrate stage
- Substrate rotation and tilt (full tilt from normal incidence to perpendicular to target)
  - o Controls deposition and etch uniformity
  - Controls etch rate and selectivity
- Substrate shutter
- Plasma bridge neutralizer

INFINITY RM UNIFORMITY		
Process	Substrate Size (7mm edge exclusion)	Uniformity (Range/2*Mean)
Deposition	150mm	2.5%
Etch	150mm	2.5%
Deposition	200mm	3.0%
Etch	200mm	3.0%

Ready to learn more about the Infinity RM Ion Beam Deposition and Etch System? Contact us today.

# ION BEAM ETCH/ASSIST/PRE-CLEAN SOURCES

- RF up to 36 cm or DC up to 21 cm
- Configured with larger sources for larger substrate sizes

#### ION BEAM ENDPOINT CONTROL

- Deposition processes:
  - Time-power
  - Quartz Crystal Monitoring (QCM): Inficon IC6 with a failsafe for time-power
- Etch processes:
  - o Time-power
  - Secondary ion mass spectrometer (OMS) or Optical emission spectrometer (OES)

